

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/084,968	ONO ET AL.	
Examiner	Art Unit	
Christina Y. Leung	2633	

SEARCHED					
Class	Subclass	Date	Examiner		
398	183	6/27/2005	Cl		
39 <u>8</u>	186	6/27/2005	Cl		
398	188	6/27/2005	U		
398	196	6/27/2005	Cl		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
398	186	6/27/2005	Q			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST text search (see search history)	6/27/2005	ce
EEE database search	6/27/2005	u
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